Form PTO 1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO.		SERIAL NO.			
			ADEMARK OFFICE	283189US0PCT		10/563,565		
				APPLICANT				
LIST OF	REFE	RENCES CITED BY A	PPLICANT	Keisuke FUNAKI, et al.				
1.0				FILING DATE		GROUP		
				January 6, 2006		2862		
				U.S. PATENT DOCUMENTS				
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	NAME CLASS		FILING DATE IF APPROPRIATE	
	AA	5,804,111	09/08/1998	Akiyoshi KOBAYASHI, et al.				
	AB	2002/0115762 A1	08/22/2002	Han-Soo CHUNG, et al.				
	AC							
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	AN							
			FO	REIGN PATENT DOCUMENTS				
		DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION YES NO		
	AO	CN 1137970A	12/18/1996	CHINA (submitting front page with English Abstract only, corr. US 5,804,111)			×	
	AP	2000-264979	09/26/2000	JAPAN (submtting English Abstract only)				
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	AU							
	AV							
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	AW							
	AX							
	AY							
	AZ				Addi	tional Refe	erences sheet(s) attached	
Examiner					Date Cor	Date Considered		
*Examiner: In	itial if re	eference is considered	l, whether or not	t citation is in conformance with MPEP 6	09; Draw lii	ne through	citation if not in	
Comormance	and no	n considered, include (John of this form	with next communication to applicant.				